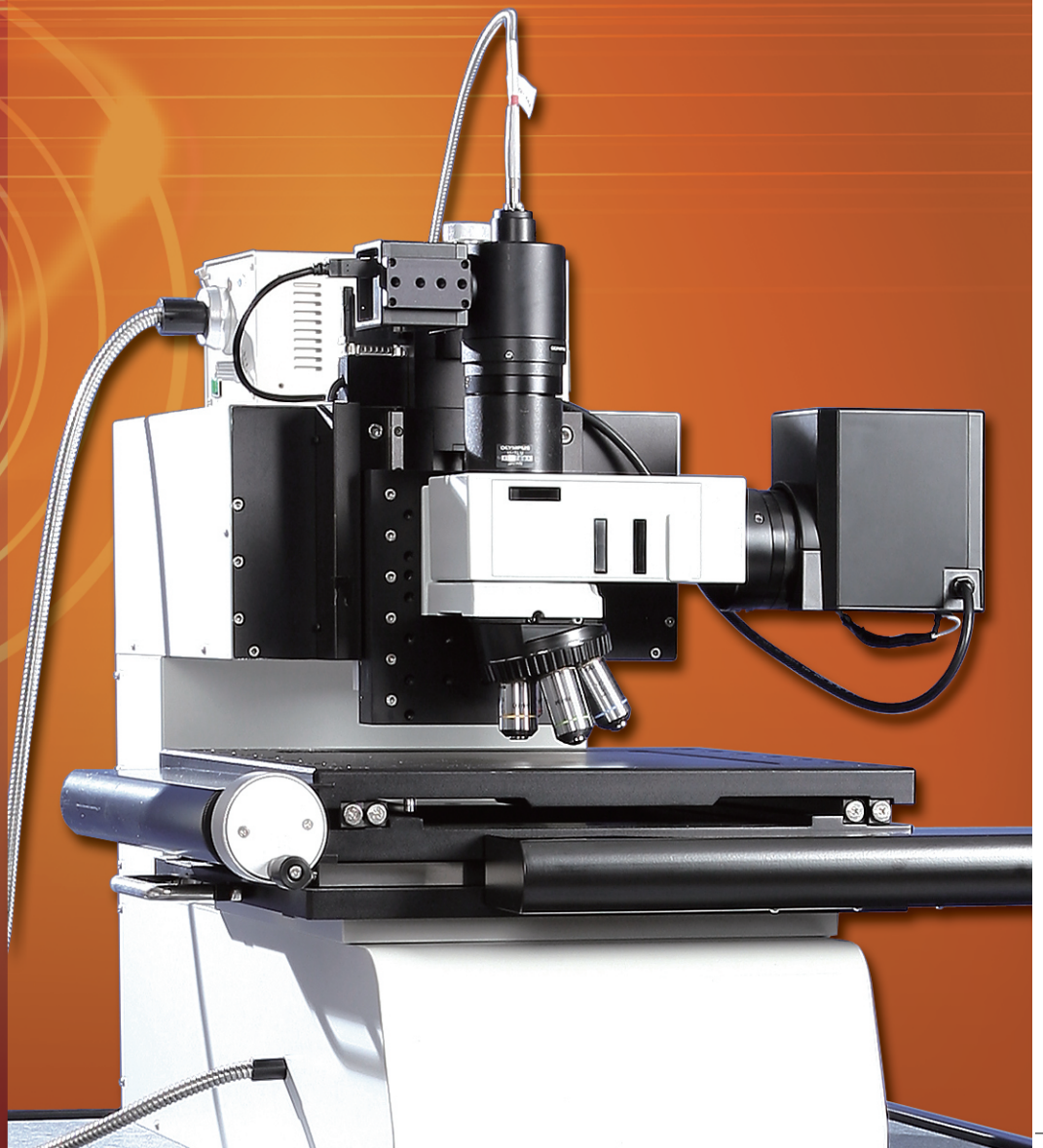


Elli-RSc

Spectroscopic Reflectometer (SR), the industry standard technology that enables to measure thin film thickness and optical constants simultaneously. Scope type SR is a low cost, film thickness measurement system that utilizes a modern small spot spectroscopic reflectometer that is built on a simple-to-use tabletop platform. It provides fast, precise measurements of single-layer films such as samples for research, as well as the top layer on film stacks of up to 3 layers in the thickness range of 100Å to 50µm. It is used for characterization of a variety of materials (e.g., dielectrics, semiconductors, organics etc.) including AR coatings, OLED and Solar Cell materials.



Elli-RSc

FEATURE

- Easy Operation & Fast Measurement
- Non-contact & Non-destructive
- High Reproducibility
- Real time Measurement
- X-Y-Z motion control
- User planned measurement script

PERFORMANCE

- Wavelength Range : 380nm ~ 1000nm
- Beam spot size : 40 μ m, 20 μ m, 10 μ m
- Thickness range : 10nm ~ 50 μ m (depends on film type)
- Number of layer : Up to 10 layer (depends on film type)
- Throughput : < 0.5 sec. per point (depends on film type)
- Repeatability : $\pm 1\text{\AA}$ on 10 times measurement

APPLICATION

Semiconductor

Si, Ge, Si₃N₄, ONO, ZnO, PR, poly-Si, GaN, GaAs

Display(including OLED)

MgO, ITO, PR, Alq₃, CuPc, NPB, PVK, PAF, PEDT-PSS

Dielectrics

SiO₂, TiO₂, Ta₂O₅, ITO, AlN, ZrO₂, Si₃N₄, Ga₂O₃, Wet Oxides

Polymer

Dye, NPP, MNA, PVA, PET, TAC, PR

Chemistry

Organic Film(OLED) & LB Thin Film

Solar Cell

SiN, a-Si, poly-Si, SiO₂

OPTION

We offer a number of options such as Anti vibration table, the Size 4 μ m of the Beam spot, Transmittance module.

